

N-Channel 650 V (D-S) Super Junction MOSFET

PRODUCT SUMMARY					
V_{DS} (V) at T_{J} max.	650				
R _{DS(on)} max. (Ω) at 25 °C	$V_{GS} = 10 V$	0.19			
Q _g max. (nC)	106				
Q _{gs} (nC)	14				
Q _{gd} (nC)	33				
Configuration	Single				

FEATURES

- Reduced t_{rr}, Q_{rr}, and I_{RRM}
- Low figure-of-merit (FOM) Ron x Qg
- Low input capacitance (Ciss)
- Low switching losses due to reduced Q_{rr}
- Ultra low gate charge (Q_a)
- Avalanche energy rated (UIS)

APPLICATIONS

- Telecommunications
- Server and telecom power supplies
- Lighting
 - High-intensity discharge (HID)
 - Fluorescent ballast lighting
- Consumer and computing - ATX power supplies
- Industrial
 - Welding
 - Battery chargers
- Renewable energy
- Solar (PV inverters)
- Switch mode power supplies (SMPS)

ABSOLUTE MAXIMUM RATINGS ($T_c = 25 \degree C$, unless otherwise noted)									
PARAMETER			SYMBOL	LIMIT	UNIT				
Drain-Source Voltage			V _{DS}	650	N				
Gate-Source Voltage			V _{GS}	± 30	V				
Continuous Drain Current (T _J = 150 °C)	V _{GS} at 10 V	$T_{\rm C} = 25 \ ^{\circ}{\rm C}$ $T_{\rm C} = 100 \ ^{\circ}{\rm C}$	– I _D	20					
	V _{GS} at 10 V	T _C = 100 °C		13	А				
Pulsed Drain Current ^a			I _{DM}	60					
Linear Derating Factor				1.7	W/°C				
Single Pulse Avalanche Energy ^b			E _{AS}	367	mJ				
Maximum Power Dissipation			P _D	208	W				
Operating Junction and Storage Temperature Range			T _J , T _{stg}	-55 to +150	°C				
Drain-Source Voltage Slope	T _J = 125 °C			37					
Reverse Diode dV/dt ^d		dV/dt	31	V/ns					
Soldering Recommendations (Peak Temperature) ^c	for 10 s			300	°C				

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature. b. $V_{DD} = 50$ V, starting T_J = 25 °C, L = 28.2 mH, R_g = 25 Ω , I_{AS} = 5.1 A.

S N-Channel MOSFET

c. 1.6 mm from case.

D²PAK (TO-263)

d. $I_{SD} \leq I_D$, dl/dt = 100 A/µs, starting T_J = 25 °C.



THERMAL RESISTANCE RATI	NGS								
PARAMETER	SYMBOL	TYP.		MAX.		UNIT			
Maximum Junction-to-Ambient	R _{thJA}	- 62							
Maximum Junction-to-Case (Drain)	R _{thJC}	- 0.5				°C/W			
SPECIFICATIONS ($T_J = 25 \ ^{\circ}C$, u	nless otherwi	se noted)							
PARAMETER	SYMBOL	TES	T CONDIT	IONS	MIN.	TYP.	MAX.	UNIT	
Static		1						L	
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} =	= 0 V, I _D =	250 µA	650	-	-	V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C,	I _D = 1 mA	-	0.67	-	V/°C	
Gate-Source Threshold Voltage (N)	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D =	250 µA	2	-	4	V	
Osta Osuma Laskana		$V_{GS} = \pm 20 V$ $V_{GS} = \pm 30 V$		-	-	± 100	nA		
Gate-Source Leakage	I _{GSS}			-	-	± 1	μA		
Zara Cata Valtaga Drain Current	V _{DS} = 520 V	= 520 V, V _G	_{iS} = 0 V	-	-	1			
Zero Gate Voltage Drain Current	te Voltage Drain Current I_{DSS} $V_{DS} = 520 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 125 \text{ °C}$		/, T _J = 125 °C	-	-	500	μA		
Drain-Source On-State Resistance	R _{DS(on)}	$V_{GS} = 10 V$	I	_D = 11 A	-	0.19	-	Ω	
Forward Transconductance	g _{fs}	V _{DS}	= 30 V, I _D	= 11 A	-	7.0	-	S	
Dynamic		*						•	
Input Capacitance	C _{iss}		$V_{GS} = 0 V$		-	2322	-		
Output Capacitance	C _{oss}	$V_{DS} = 100 V,$ f = 1 MHz		-	105	-	pF		
Reverse Transfer Capacitance	C _{rss}			-	4	-			
Effective Output Capacitance, Energy Related ^a	C _{o(er)}	$V_{DS} = 0$ V to 520 V, $V_{GS} = 0$ V		-	84	-			
Effective Output Capacitance, Time Related ^b	C _{o(tr)}			-	293	-			
Total Gate Charge	Qg				-	71	106	1	
Gate-Source Charge	Q _{gs}	$V_{GS} = 10 \text{ V}$ $I_D = 11 \text{ A}, V_{DS} = 520 \text{ V}$		-	14	-	nC		
Gate-Drain Charge	Q _{gd}				-	33	-		
Turn-On Delay Time	t _{d(on)}	V_{DD} = 520 V, I _D = 11 A, V _{GS} = 10 V, R _g = 9.1 Ω		-	22	44	- ns		
Rise Time	t _r			-	34	68			
Turn-Off Delay Time	t _{d(off)}			-	68	102			
Fall Time	t _f			-	42	84			
Gate Input Resistance	Rg	f = 1 MHz, open drain		-	0.78	-	Ω		
Drain-Source Body Diode Characteristic	s								
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	21	A		
Pulsed Diode Forward Current	I _{SM}			-	-	53			
Diode Forward Voltage	V _{SD}	T _J = 25 °C, I _S = 11 A, V _{GS} = 0 V		-	0.9	1.2	V		
Reverse Recovery Time	t _{rr}	$T_J = 25 \text{ °C}, I_F = I_S = 11 \text{ A},$ dl/dt = 100 A/µs, V _R = 25 V		-	160	-	ns		
Reverse Recovery Charge	Q _{rr}			-	1.2	-	μC		
Reverse Recovery Current	I _{RRM}			-	14	-	A		

Notes

a. $C_{oss(er)}$ is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} . b. $C_{oss(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} .



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

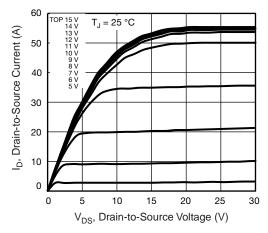


Fig. 1 - Typical Output Characteristics

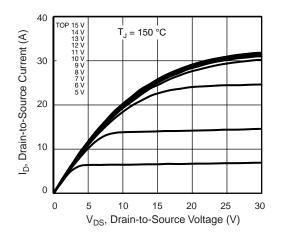


Fig. 2 - Typical Output Characteristics

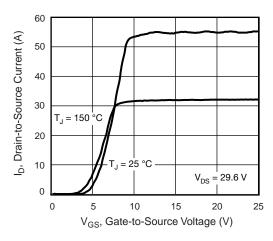


Fig. 3 - Typical Transfer Characteristics

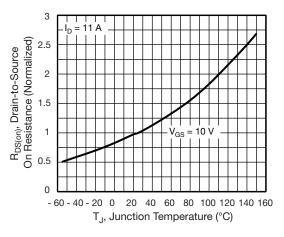


Fig. 4 - Normalized On-Resistance vs. Temperature

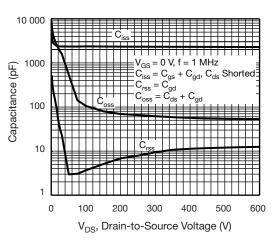


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

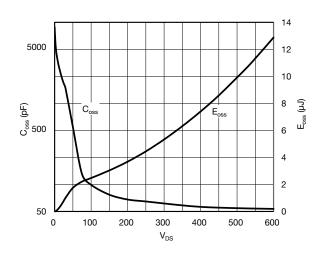


Fig. 6 - C_{oss} and E_{oss} vs. V_{DS}



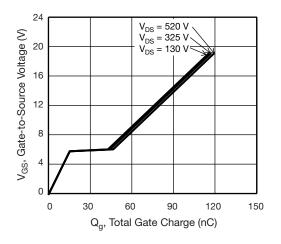


Fig. 7 - Typical Gate Charge vs. Gate-to-Source Voltage

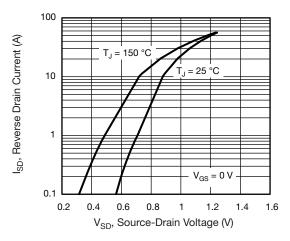


Fig. 8 - Typical Source-Drain Diode Forward Voltage

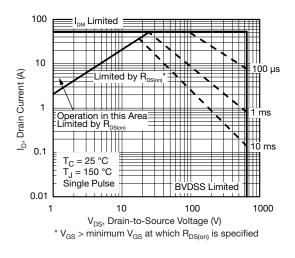


Fig. 9 - Maximum Safe Operating Area

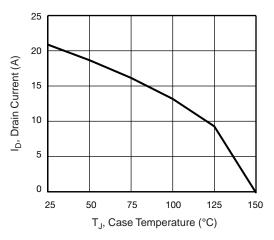


Fig. 10 - Maximum Drain Current vs. Case Temperature

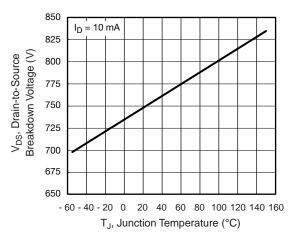


Fig. 11 - Temperature vs. Drain-to-Source Voltage



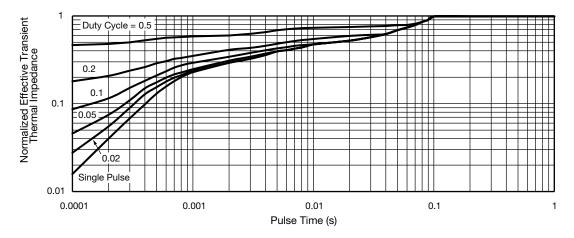


Fig. 12 - Normalized Thermal Transient Impedance, Junction-to-Case

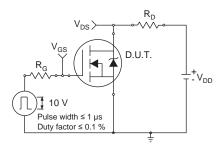


Fig. 13 - Switching Time Test Circuit

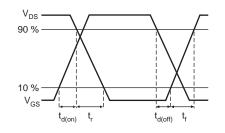


Fig. 14 - Switching Time Waveforms

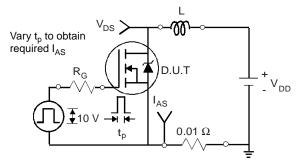


Fig. 15 - Unclamped Inductive Test Circuit

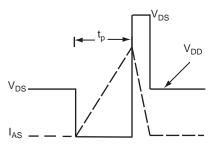


Fig. 16 - Unclamped Inductive Waveforms

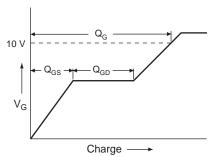
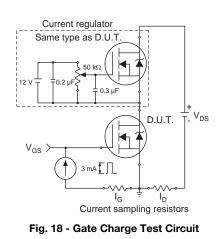
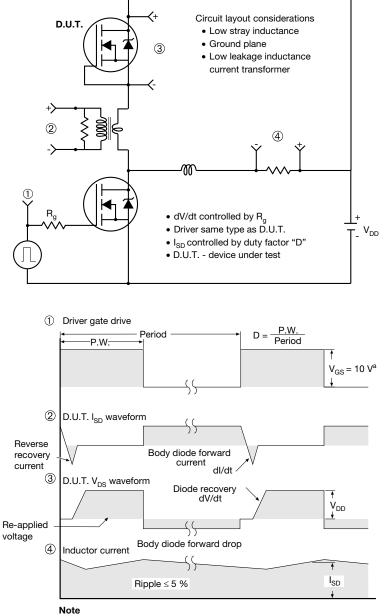


Fig. 17 - Basic Gate Charge Waveform





Peak Diode Recovery dV/dt Test Circuit

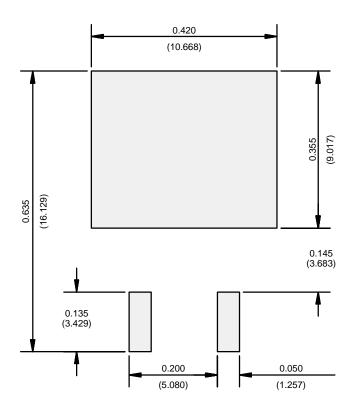


a. $V_{GS} = 5$ V for logic level devices

Fig. 19 - For N-Channel



RECOMMENDED MINIMUM PADS FOR D²PAK: 3-Lead



Recommended Minimum Pads Dimensions in Inches/(mm)



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